

# GE85T08

## N-CHANNEL ENHANCEMENT MODE POWER MOSFET

BVDSS	80V
RDS(ON)	13mΩ
ID	75A

### Description

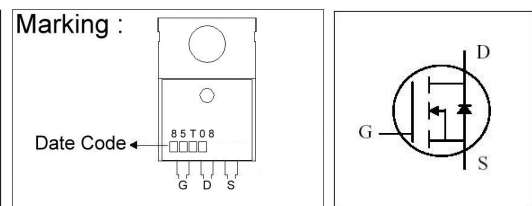
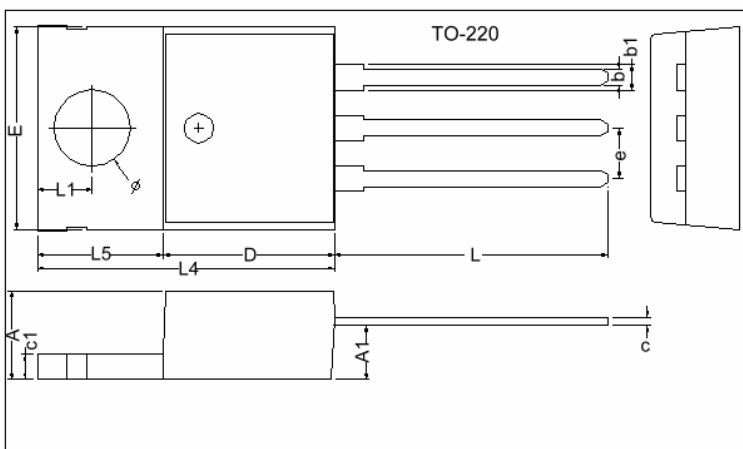
The GE85T08 provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The through-hole version (TO-220) is available for low-profile applications and suited for low voltage applications such as DC/DC converters.

### Features

- \*Simple Drive Requirement
- \*Lower On-resistance
- \*Fast Switching

### Package Dimensions



REF.	Millimeter		REF.	Millimeter	
	Min.	Max.		Min.	Max.
A	4.40	4.80	c1	1.25	1.45
b	0.76	1.00	b1	1.17	1.47
c	0.36	0.50	L	13.25	14.25
D	8.60	9.00	e	2.54 REF.	
E	9.80	10.4	L1	2.60	2.89
L4	14.7	15.3	Ø	3.71	3.96
L5	6.20	6.60	A1	2.60	2.80

### Absolute Maximum Ratings

Parameter	Symbol	Ratings	Unit
Drain-Source Voltage	$V_{DS}$	80	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Continuous Drain Current, $V_{GS}@10V$	$I_D @T_C=25^\circ C$	75	A
Continuous Drain Current, $V_{GS}@10V$	$I_D @T_C=100^\circ C$	48	A
Pulsed Drain Current <sup>1</sup>	$I_{DM}$	260	A
Total Power Dissipation	$P_D @T_C=25^\circ C$	138	W
Linear Derating Factor		1.11	W/ $^\circ C$
Single Pulse Avalanche Energy <sup>3</sup>	$E_{AS}$	450	mJ
Avalanche Current	$I_{AR}$	30	A
Operating Junction and Storage Temperature Range	$T_j, T_{stg}$	-55 ~ +150	$^\circ C$

### Thermal Data

Parameter	Symbol	Value	Unit
Thermal Resistance Junction-case Max.	$R_{thj-c}$	0.9	$^\circ C/W$
Thermal Resistance Junction-ambient Max.	$R_{thj-a}$	62	$^\circ C/W$

**Electrical Characteristics(T<sub>j</sub> = 25°C Unless otherwise specified)**

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Drain-Source Breakdown Voltage	$BV_{DSS}$	80	-	-	V	$V_{GS}=0, I_D=1mA$
Breakdown Voltage Temperature Coefficient	$\Delta BV_{DSS} / \Delta T_j$	-	0.09	-	V/°C	Reference to 25°C, $I_D=1mA$
Gate Threshold Voltage	$V_{GS(th)}$	1.0	-	3.0	V	$V_{DS}=V_{GS}, I_D=250\mu A$
Forward Transconductance	$g_{fs}$	-	70	-	S	$V_{DS}=10V, I_D=45A$
Gate-Source Leakage Current	$I_{GSS}$	-	-	±100	nA	$V_{GS}= \pm 20V$
Drain-Source Leakage Current(T <sub>j</sub> =25°C)	$I_{DSS}$	-	-	10	uA	$V_{DS}=80V, V_{GS}=0$
Drain-Source Leakage Current(T <sub>j</sub> =150°C)		-	-	100	uA	$V_{DS}=64V, V_{GS}=0$
Static Drain-Source On-Resistance <sup>2</sup>	$R_{DS(ON)}$	-	-	13	mΩ	$V_{GS}=10V, I_D=45A$
		-	-	18		$V_{GS}=4.5V, I_D=25A$
Total Gate Charge <sup>2</sup>	$Q_g$	-	63	100	nC	$I_D=45A$ $V_{DS}=64V$ $V_{GS}=4.5V$
Gate-Source Charge	$Q_{gs}$	-	23	-		
Gate-Drain ("Miller") Charge	$Q_{gd}$	-	38	-		
Turn-on Delay Time <sup>2</sup>	$T_{d(on)}$	-	30	-	ns	$V_{DS}=40V$ $I_D=45A$ $V_{GS}=10V$ $R_G=10\Omega$ $R_D=0.89\Omega$
Rise Time	$T_r$	-	100	-		
Turn-off Delay Time	$T_{d(off)}$	-	144	-		
Fall Time	$T_f$	-	173	-		
Input Capacitance	$C_{iss}$	-	6300	10080	pF	$V_{GS}=0V$ $V_{DS}=25V$ $f=1.0MHz$
Output Capacitance	$C_{oss}$	-	670	-		
Reverse Transfer Capacitance	$C_{rss}$	-	350	-		
Gate Resistance	$R_g$	-	1.1	1.7		

**Source-Drain Diode**

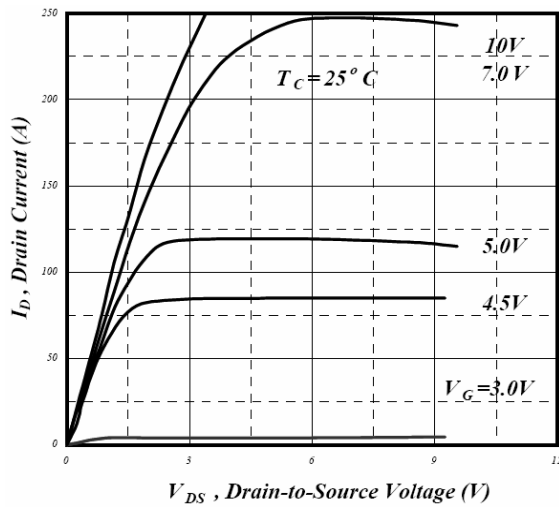
Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Forward On Voltage <sup>2</sup>	$V_{SD}$	-	-	1.3	V	$I_S=45A, V_{GS}=0V$
Reverse Recovery Time <sup>2</sup>	$T_{rr}$	-	47	-	ns	$I_S=20A, V_{GS}=0V$ $di/dt=100A/\mu s$
Reverse Recovery Charge	$Q_{rr}$	-	86	-	nC	

Notes: 1. Pulse width limited by safe operating area.

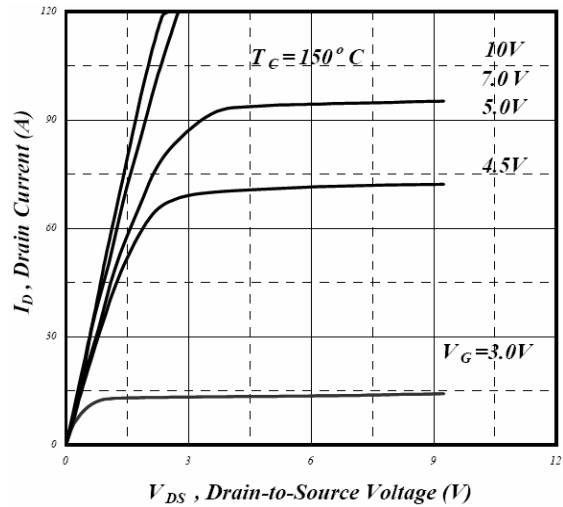
2. Pulse width ≤ 300us, duty cycle ≤ 2%.

3. Staring T<sub>j</sub>=25°C, V<sub>DD</sub>=30V, L=1mH, R<sub>G</sub>=25Ω, I<sub>AS</sub>=30A.

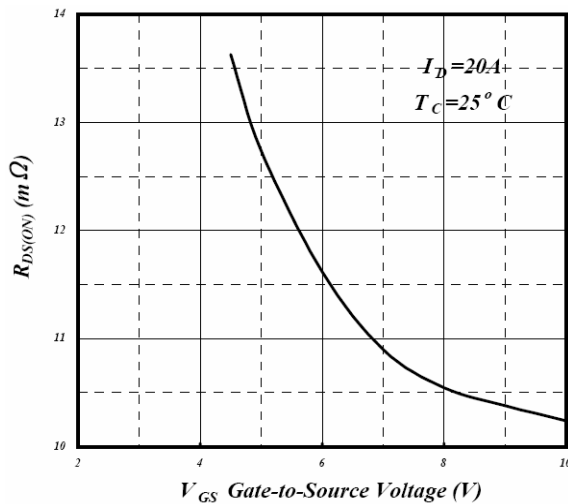
## Characteristics Curve



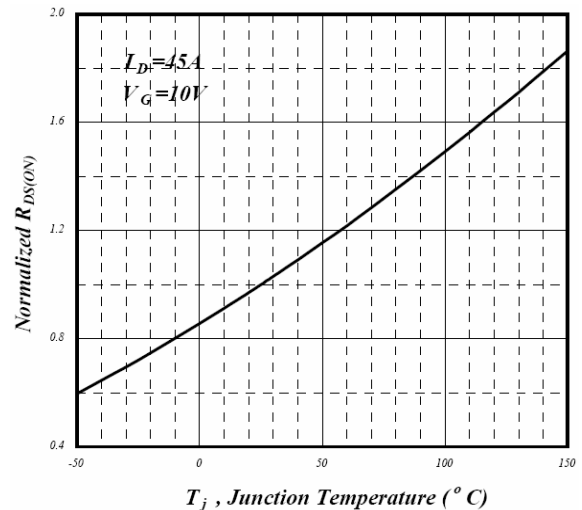
**Fig 1. Typical Output Characteristics**



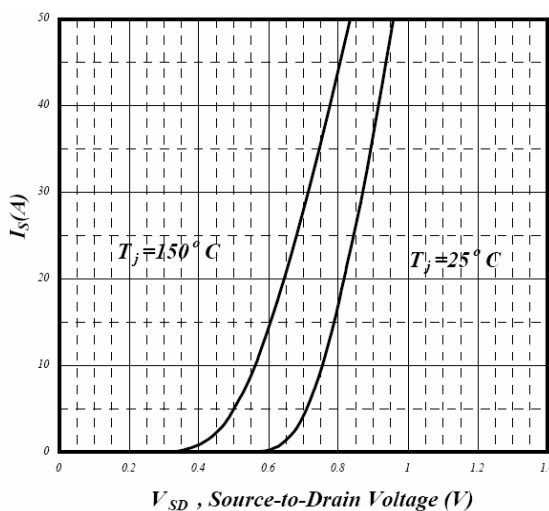
**Fig 2. Typical Output Characteristics**



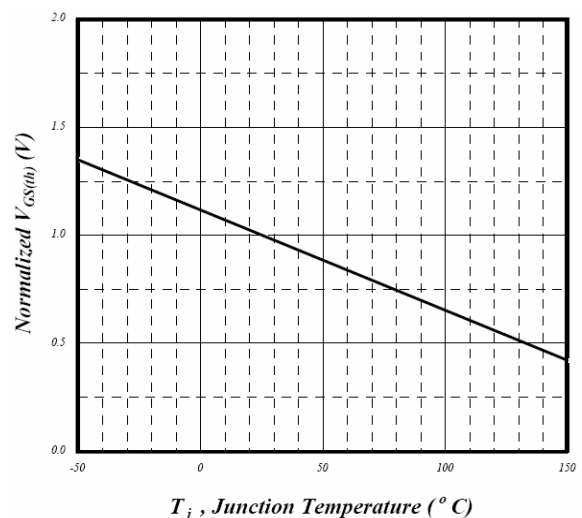
**Fig 3. On-Resistance v.s. Gate Voltage**



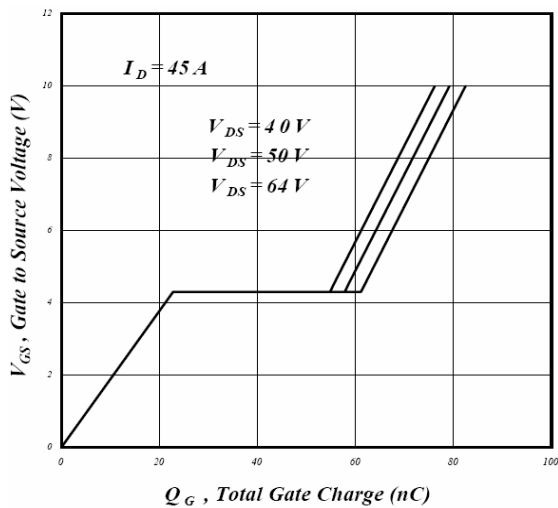
**Fig 4. Normalized On-Resistance v.s. Junction Temperature**



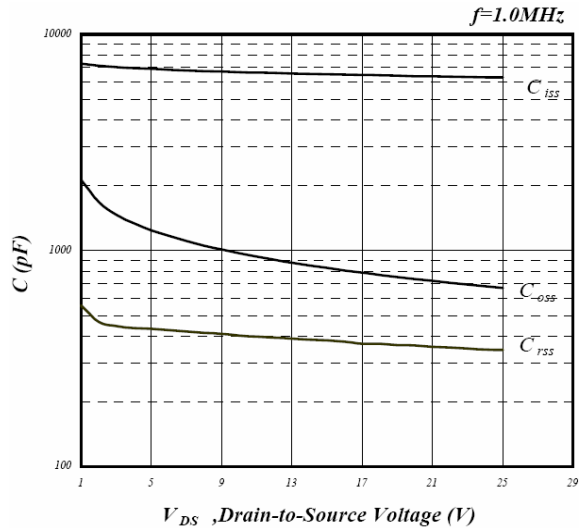
**Fig 5. Forward Characteristics of Reverse Diode**



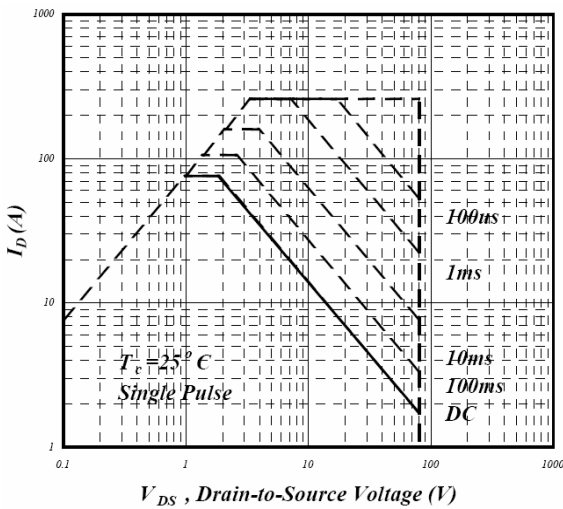
**Fig 6. Gate Threshold Voltage v.s. Junction Temperature**



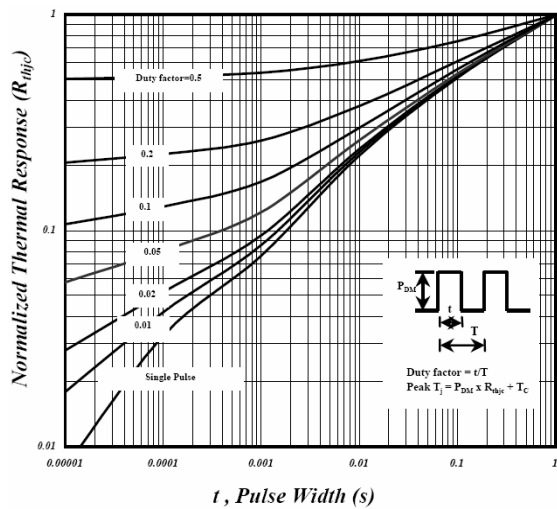
**Fig 7. Gate Charge Characteristics**



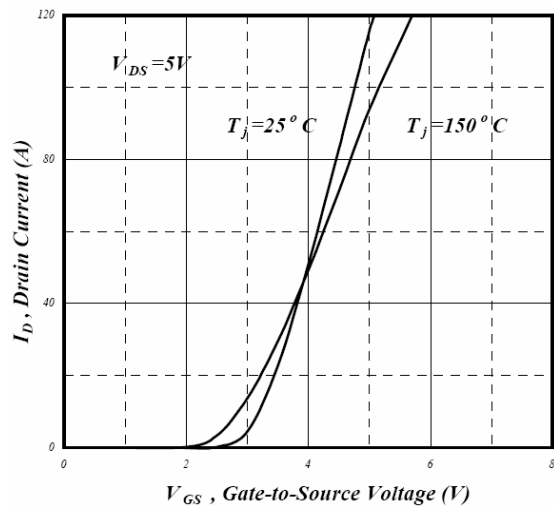
**Fig 8. Typical Capacitance Characteristics**



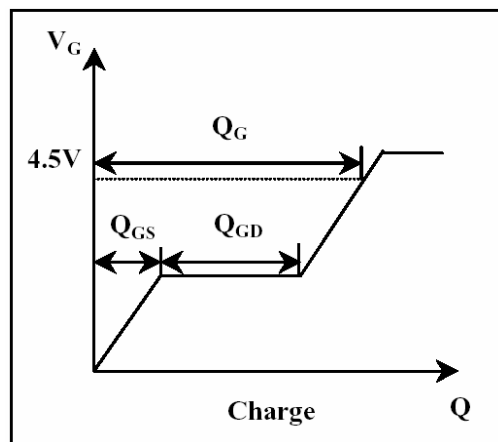
**Fig 9. Maximum Safe Operating Area**



**Fig 10. Effective Transient Thermal Impedance**



**Fig 11. Transfer Characteristics**



**Fig 12. Gate Charge Waveform**

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